

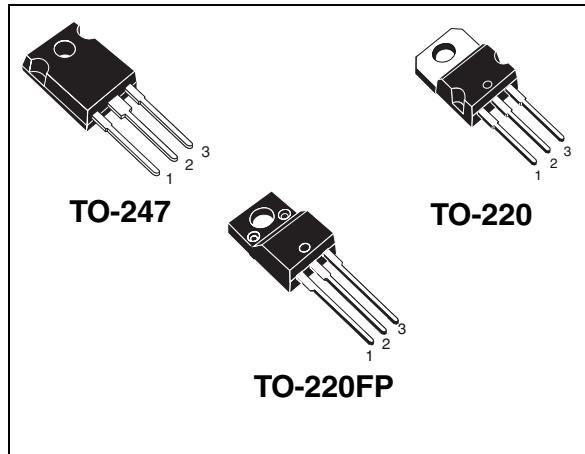
STF34NM60N STP34NM60N, STW34NM60N

N-channel 600 V, 0.092 Ω , 29 A MDmesh™ II Power MOSFET
TO-220, TO-247, TO-220FP

Features

Type	V_{DSS}	$R_{DS(on)}$ max.	I_D	P_{TOT}
STF34NM60N	600 V	0.105 Ω	29 A	40 W
STP34NM60N	600 V	0.105 Ω	29 A	210 W
STW34NM60N	600 V	0.105 Ω	29 A	210 W

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance



Application

Switching applications

Description

These devices are made using the second generation of MDmesh™ technology. This revolutionary Power MOSFET associates a new vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

Figure 1. Internal schematic diagram

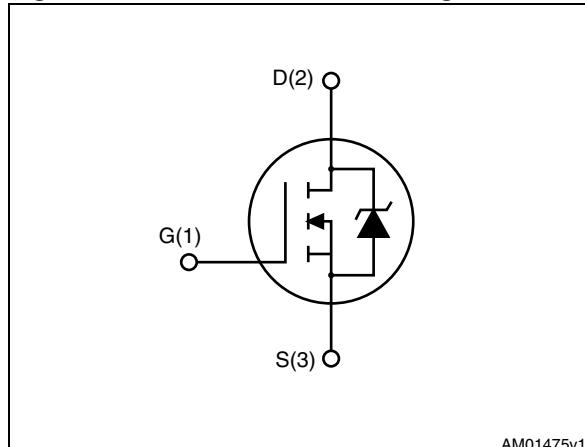


Table 1. Device summary

Order codes	Marking	Package	Packaging
STF34NM60N		TO-220FP	
STP34NM60N	34NM60N	TO-220	Tube
STW34NM60N		TO-247	

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value		Unit
		TO-220, TO-247	TO-220FP	
V_{DS}	Drain-source voltage ($V_{GS} = 0$)	600		V
V_{GS}	Gate- source voltage	± 25		V
I_D	Drain current (continuous) at $T_C = 25^\circ\text{C}$	29	29 (1)	A
I_D	Drain current (continuous) at $T_C = 100^\circ\text{C}$	18	18	A
$I_{DM}^{(2)}$	Drain current (pulsed)	116	116	A
P_{TOT}	Total dissipation at $T_C = 25^\circ\text{C}$	210	40	W
I_{AR}	Avalanche current, repetitive or not-repetitive (pulse width limited by T_J max)	10.5		A
E_{AS}	Single pulse avalanche energy (starting $T_J = 25^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50$ V)	345		mJ
$dv/dt^{(3)}$	Peak diode recovery voltage slope	15		V/ns
V_{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink ($t = 1$ s; $T_C = 25^\circ\text{C}$)		1200	V
T_{stg}	Storage temperature	- 55 to 150		$^\circ\text{C}$
T_J	Max. operating junction temperature	150		

1. Limited only by maximum temperature allowed.
2. Pulse width limited by safe operating area.
3. $I_{SD} \leq 29$ A, $di/dt \leq 400$ A/ μs , V_{DS} peak $\leq V_{(BR)DSS}$, $V_{DD} = 80\%$ $V_{(BR)DSS}$

Table 3. Thermal data

Symbol	Parameter	TO-220	TO-247	TO-220FP	Unit
$R_{thj-case}$	Thermal resistance junction-case max	0.60		3.13	$^\circ\text{C}/\text{W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max	62.5	50	62.5	$^\circ\text{C}/\text{W}$
T_I	Maximum lead temperature for soldering purpose	300			$^\circ\text{C}$

2 Electrical characteristics

($T_{CASE} = 25^\circ\text{C}$ unless otherwise specified)

Table 4. On/off states

Symbol	Parameter	Test conditions	Value			Unit
			Min.	Typ.	Max.	
$V_{(BR)DSS}$	Drain-source breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0$	600			V
I_{DSS}	Zero gate voltage drain current ($V_{GS} = 0$)	$V_{DS} = \text{Max rating}$ $V_{DS} = \text{Max rating } @ 125^\circ\text{C}$			1 100	μA μA
I_{GSS}	Gate-body leakage current ($V_{DS} = 0$)	$V_{GS} = \pm 25 \text{ V}$			100	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2	3	4	V
$R_{DS(\text{on})}$	Static drain-source on resistance	$V_{GS} = 10 \text{ V}, I_D = 14.5 \text{ A}$		0.092	0.105	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance			2722		pF
C_{oss}	Output capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}$,	-	173	-	pF
C_{rss}	Reverse transfer capacitance	$V_{GS} = 0$		1.75		pF
$C_{oss \text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{GS} = 0, V_{DS} = 0 \text{ to } 480 \text{ V}$	-	458	-	pF
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300 \text{ V}, I_D = 14.5 \text{ A}$		17		ns
t_r	Rise time	$R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$		34		ns
$t_{d(off)}$	Turn-off delay time		-	106	-	ns
t_f	Fall time			67		ns
Q_g	Total gate charge	$V_{DD} = 480 \text{ V}, I_D = 29 \text{ A}$	-	83.6		nC
Q_{gs}	Gate-source charge	$V_{GS} = 10 \text{ V}$		14	-	nC
Q_{gd}	Gate-drain charge			45		nC
R_g	Gate input resistance	f=1MHz Gate DC Bias=0 Test signal level=20 mV Open drain	-	2.9	-	Ω

1. $C_{oss \text{ eq.}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 6. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		29	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)				116	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 29 \text{ A}, V_{GS} = 0$	-		1.6	V
t_{rr}	Reverse recovery time	$I_{SD} = 29 \text{ A}, V_{DD} = 60 \text{ V}$		408		ns
Q_{rr}	Reverse recovery charge	$dI/dt = 100 \text{ A}/\mu\text{s}$	-	8		nC
I_{RRM}	Reverse recovery current			39		A
t_{rr}	Reverse recovery time	$I_{SD} = 29 \text{ A}, V_{DD} = 60 \text{ V}$		480		ns
Q_{rr}	Reverse recovery charge	$dI/dt = 100 \text{ A}/\mu\text{s},$	-	10		nC
I_{RRM}	Reverse recovery current	$T_J = 150 \text{ }^\circ\text{C}$		42		A

1. Pulse width limited by safe operating area
2. Pulsed: Pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for TO-220

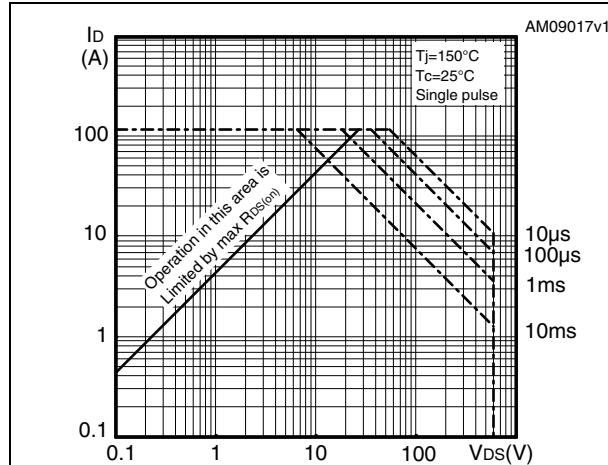


Figure 3. Thermal impedance for TO-220

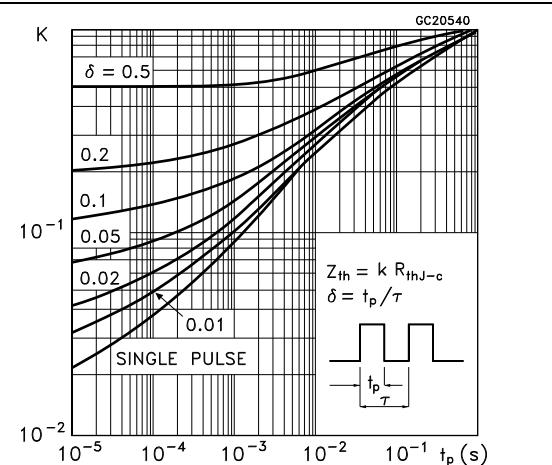


Figure 4. Safe operating area for TO-220FP

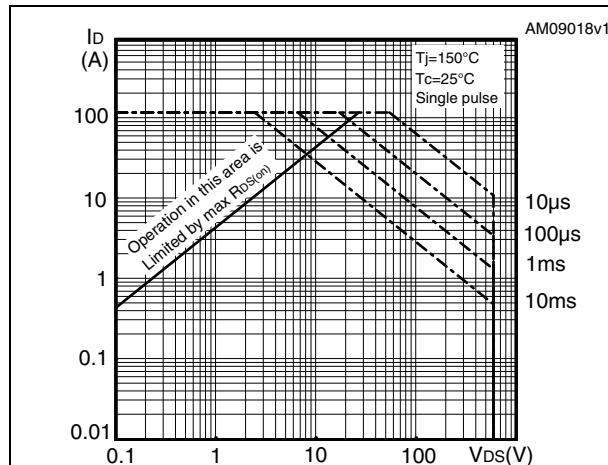


Figure 5. Thermal impedance for TO-220FP

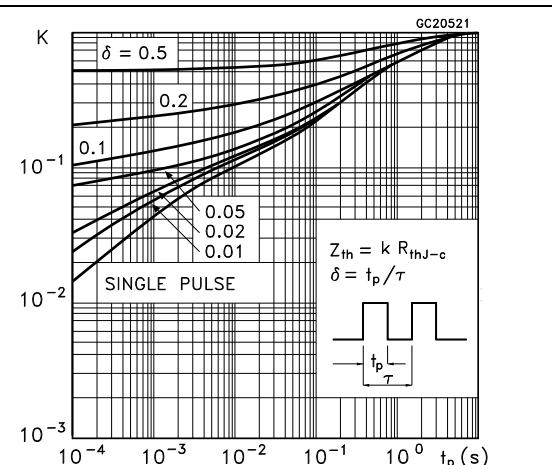


Figure 6. Safe operating area for TO-247

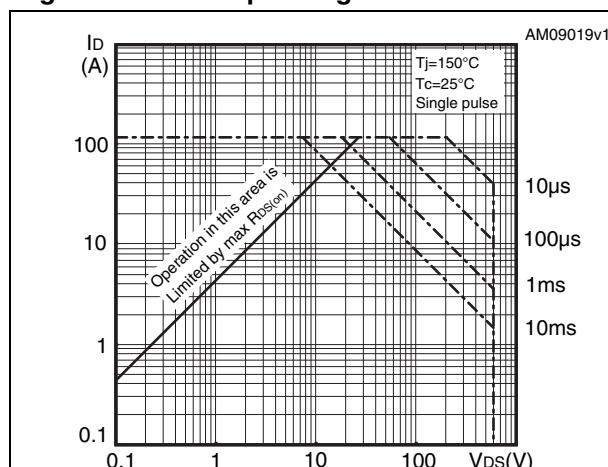


Figure 7. Thermal impedance for TO-247

